Searcn Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination CHOU, WEN SAN	
10/705,627		
Examiner	Art Unit	
Patrick Hamo	3746	

SEARCHED					
Class	Subclass	Date	Examiner		
417	415	11/15/2006	РН		
upolat	عط	9/10/07	P4		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
				
			1	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
417/415 serached as initially classified	11/15/2006	PH			
updakd	9/10/07	pu			
test search, see EAST search results	9/0/07	PU			